

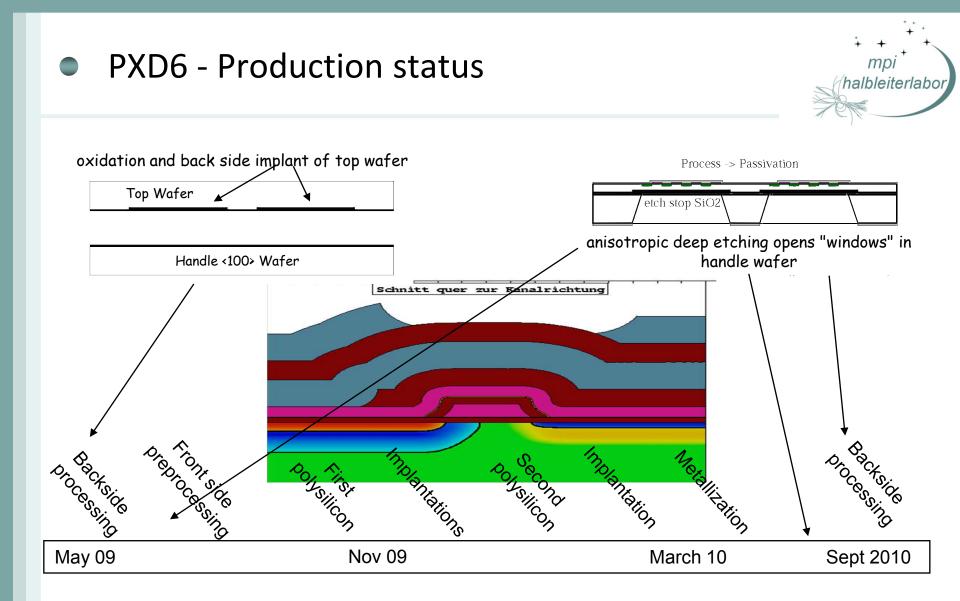


PXD6 Status and Hybrid Boards

Status: PXD6 production Hybrid Boards

TestBeam Workshop Göttingen - 15./16. April 2010

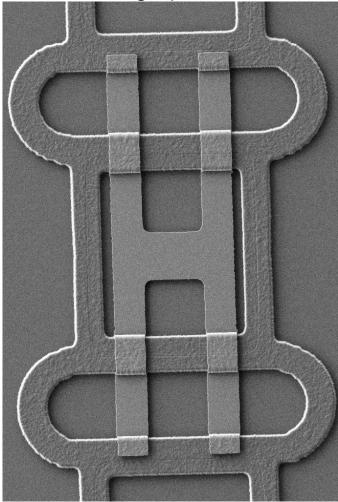
C. Koffmane HLL, MPI für Physik



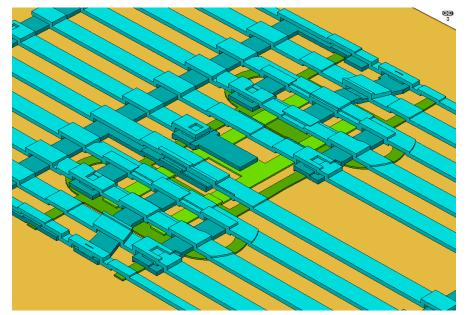


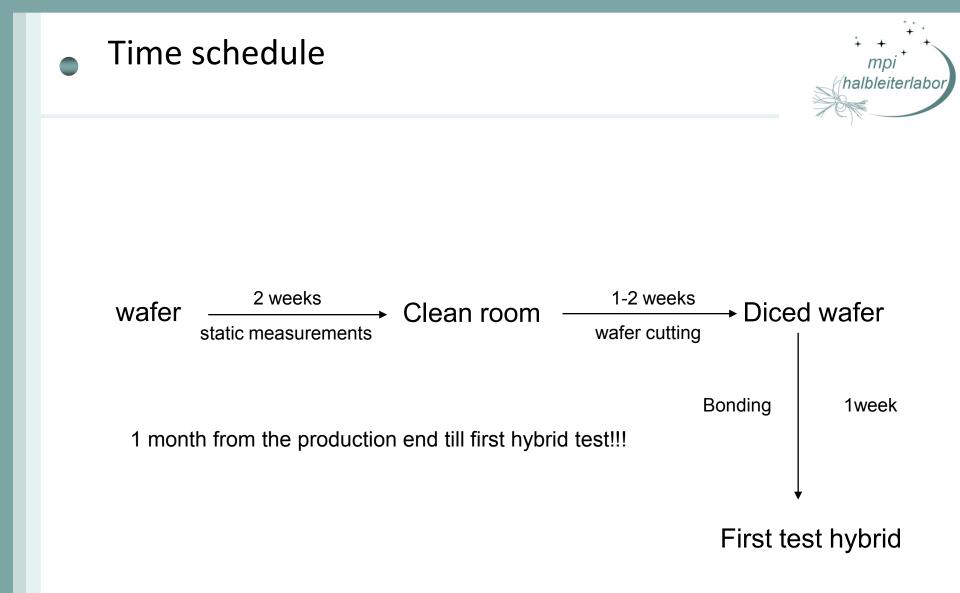


REM micrograph

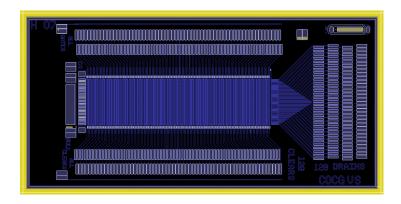


3D model

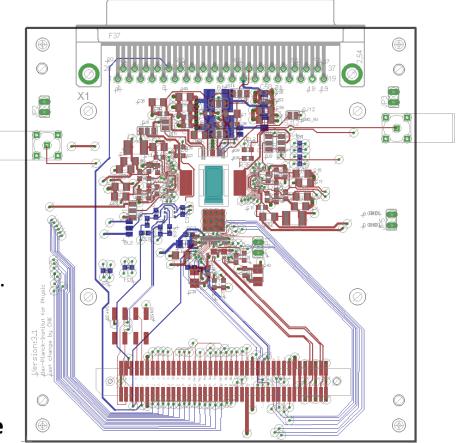




Version 1: PXD6 – ILC Type with Hybrid 3.1 - S3B system (CURO + SW3)



- PXD6 ILC Design can be used with Hybrid 3.1 (electrical identical with Hybrid 3.0 cut-out 4.3 x 9mm² instead of 5.3 x 10 mm²).
- PXD6 Wafer:
 - 3 x ILC type (24 x 24 μm² type used as DUT in TB2009)
 - 3 x ILC type VS (20 x 20 μm² type as the best DUT TB2009)



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Version 1: PXD6 – ILC Type with Hybrid 3.1 - S3B system (CURO + SW3)



Pro:

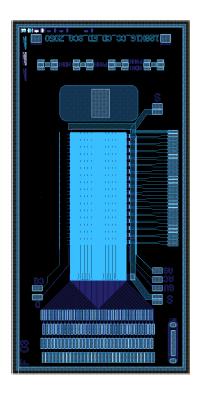
- start with a known matrix design: "ILC type"
- well known system (Hybrid + Power Supply + Readout DAQ)
- proof of principle of thin matrix designs

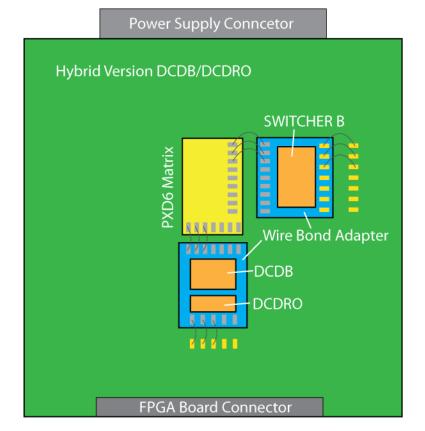
Contra:

- reduced sensor thickness (50 μ m) will reduce SNR
 - SNR will only be 1/9 of the PXD5 matrices

Version 2: PXD6 and Hybrid - DCD-B/DCDRO + SWB







- Design is ongoing
- DCDB and DCDRO converter chip on one adapter
- SWB on another adapter

Version 2: PXD6 and Hybrid - DCD-B/DCDRO + SWB

Status:

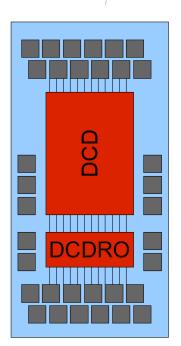
 redesign of the wire bond adapter for DCD-B/DCDRO and SWITCHER-B

ightarrow due to small pitch of the wire bond pads

 \rightarrow this design is on-going; wafer for fabrication ready @ HLL (will be the same wafer as for DHP wire bond adapter)

- hybrid design will be finalized as soon as wire bond design is freezed (2 weeks design effort; 6 weeks PCB production)

- schematic is done; same pin assignment as DCD-B/DCDRO single test boards designed by Christian Kreidel





Version 2: PXD6 and Hybrid - DCD-B/DCDRO + SWB



Pro:

- designed for Belle-II matrices
- noise of DCD-B should be less then noise of CURO
- fast readout (300MHz) will be possible

Contra:

- new DAQ software necessary
- Bonn power supplies have to be modified (for use of one DUT bench power supplies can be used)

Version 3: PXD5 and Hybrid – DCD2/SW3

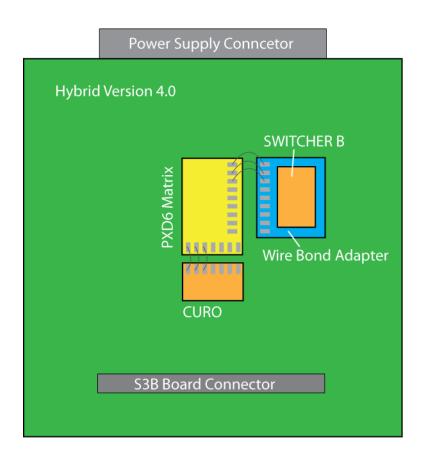
- Pro: boards are available- first long matrix in a testbeam
- Contra: only the lower rows can be connected (one SW3)
 - only 6 columns are connected
 - DAQ is necessary (same as for Version 2)
 - at the moment bench power supplies are used





Version 4: PXD6 and Hybrid 4.0 for S3B System (CURO & SWB)

- Hybrid 4.0 is a re-design of Hybrid 3.0 with new SWB and CURO
- Minor changes of the current power Supply and DAQ system
 - Power Supply of the SWB (single channel for Clear High/Gate Low – no staggered use of three power supply channels)
 - JTAG Protocol for Slow Control
 - Clear and Gate Sequence (new FPGA firmware)



→Only back-up option in case there are problems with DCD-B/DCDRO No priority at the moment.

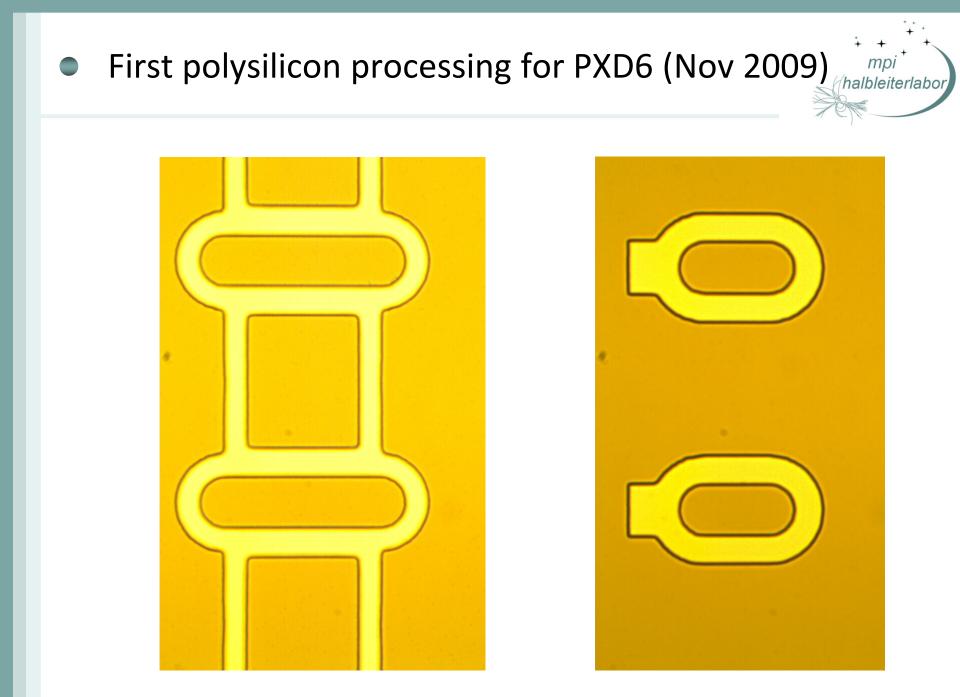
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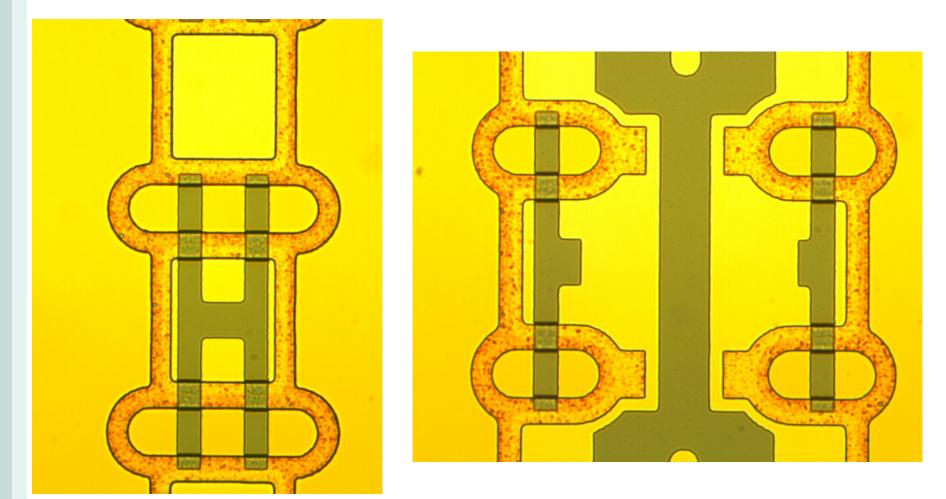
Thank you!

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Second polysilicon processing for PXD6 before oxidation



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Second polysilicon processing for PXD6 after oxidation



